



COPY OF PAPERS
ORIGINALLY FILED

#4/A R 8/22/02

Attorney Docket: 3319.3A (02US2)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: James W. Overbeck
Serial No: 10/034,620
Filed: 12/27/2001
For: WIDE FIELD OF VIEW AND HIGH SPEED SCANNING MICROSCOPY

Examiner: <not yet assigned>
Art Unit: 2872

BOX MISSING PARTS

COMMISSIONER FOR PATENTS
WASHINGTON, D.C. 20231

PRELIMINARY AMENDMENT

Prior to examination, please amend this application as follows:

In the claims:

Please cancel the pending claims 1 - 61, and enter the following new claim:

62. A wide field of view scanner, comprising:
a scanning assembly constructed to provide a light beam emitted from a light source in a scanning motion to an examined surface;
an objective lens associated with the scanning assembly arranged to provide an optical path from the examined surface to a light detector;
a translation system constructed to produce movement of the examined surface;
and
a data collection control and processing unit arranged to collect data during the scanning motion and process the collected data.

In the Abstract:

Please enter the following new Abstract

A wide field of view scanning microscope includes a light source, a light detector, optics, a scanning assembly, a translation system, and a data collection control and processing unit. The scanning assembly is constructed to provide from the light source a light beam in a scanning motion to an examined surface. The optics includes an objective lens associated with the scanning assembly arranged to provide an optical path to the light detector. The translation system is constructed to produce a